1	[0098]	ABSTRACT OF THE DISCLOSURE
2	[0099]	We have developed a method of PECVD depositing a-SiN $_x$:H films which are
3	useful in	a TFT device as gate dielectric and passivation layers, when a series of TFT
4	devices are arrayed over a substrate having a surface area larger than about 1 m ² , which	
5	may be in	the range of about 4.1 m ² , and even as large as 9 m ² . The a-SiN _x :H films
6	provide a	uniformity of film thickness and uniformity of film properties, including
7	chemical	composition, which are necessary over such large substrate surface areas. The
8	films prod	duced by the method are useful for both liquid crystal active matrix displays and
9	for organi	ic light emitting diode control.